Equipment Introduction

XMD automatic testing system

The LIV test of laser is realized by controlling the current source and high-speed optical power meter. According to the test results, relevant parameters such as Ith and slope efficiency of the laser are analyzed, the optical power value and spectral characteristics of the laser at a fixed current are tested, and spectral information such as central wavelength and side mode suppression ratio are extracted. In terms of software, it can process the original test data, store the processed data in the background database, and judge whether the test is qualified.





Technology & Function	Specification & Parameters
 Supports the setting of parameters such as operating temperature, power supply mode, current and voltage; Supports current step setting to realize current scanning while recording optical power; Supports operating temperature step setting to realize temperature scanning while recording optical power; Supports automatic measurement of spectral parameters such as wavelength and side mode suppression ratio; Supports the test of two photocurrents, and automatically compares the two currents to judge whether the results are qualified; Supports TEC internal resistance automatic test and laser LIV automatic test; Supports automatic temperature-power scan test, with configurable test conditions and specifications; Supports processing the original test data, and stores the processed data into the background database, displays the test results in real time, automatically judges whether the test is qualified, and saves the process data; Supports comparison of test data of different processes. 	 Clamping repeatability of collimating optical fiber: ±1 um Central wavelength test accuracy: 0.05 nm TEC ACR test repeatability: 1% Maximum operating current of TEC: 3A Optical power repeatability test: Repeat the measurement for 10 times, and the difference between the maximum and minimum values shall be ≤0.1 dB